Name of Accreditation Program	JCSS Accreditation Program		
Accreditation Identification	JCSS 0029 Calibration		
Name of Conformity Assessment Body	Measurement and Calibration Center, Japan Quality Assurance Organization		
Name of Legal Entity	Japan Quality Assurance Organization JCN 9010005016585		
Inquiry Point	Sales Division TEL: +81-42-679-0144 FAX: +81-42-679-0187		

<sup>\*</sup>JCN: Japan Corporate Number



#### **Certificate of Accreditation**

International Accreditation Japan (IAJapan) hereby accredits the following conformity assessment body as a calibration laboratory of Japan Calibration Service System.

Accreditation Identification: JCSS 0029 Calibration

Name of Conformity Assessment Body: Measurement and Calibration Center,

Japan Quality Assurance Organization

Name of Legal Entity: Japan Quality Assurance Organization

Location of Conformity Assessment Body: 4-4-4 Minamiosawa, Hachioji-shi, Tokyo 192-0364,

**JAPAN** 

Scope of Accreditation: Length, Mass, Temperature, Angle, Fluid Flow,

Acceleration, Electricity (High Frequency) &

Electromagnetic Fields, Force, Acoustics & Ultrasound,

Radiation & Radioactivity & Neutron, Hardness,

Humidity (as the following pages)

Accreditation Requirement: ISO/IEC 17025:2017\*

\* The relevant accreditation requirements described in the Accreditation

Scheme Document for JCSS are also applied.

Effective Date of Accreditation: 2024-03-29

Expiry Date of Accreditation: 2028-03-28

Date of Initial Accreditation: 1994-05-02

SAITO Kazunori

Chief Executive, International Accreditation Japan (IAJapan)

National Institute of Technology and Evaluation

<sup>-</sup> International Accreditation Japan (IAJapan) is a laboratory accreditation body which has signed MRAs of ILAC (International Laboratory Accreditation Cooperation) and APAC (Asia Pacific Accreditation Cooperation).

<sup>-</sup> MRA requirements are, in addition to relevant international standards and guides, requirements for participation in proficiency testing programs, surveillance and reassessment, and the policy for the traceability of measurement for MRA purpose.

<sup>-</sup> This laboratory fulfills ISO/IEC 17025:2017 General requirements for the competence of testing and calibration laboratories. This accreditation means this laboratory meets both the technical competence requirements and management system requirements that are necessary for it to consistently deliver technically valid test results and calibrations (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

<sup>-</sup> The latest accreditation information is publicly available on IAJapan Website as an accreditation certificate.

General Field of Calibration: Length

Date of Initial Accreditation of the Field: 1994-05-02

Laboratory's permanent facility/On-site Calibration: Laboratory's permanent facility

Calibration and Measurement Capabilities

Calibration Procedures# and Type of Instruments/Materials to be calibrated		Range	Expanded Uncertainty (Level of Confidence Approximately 95 %) (L (mm): Nominal Length)
Laser Wavelength	Frequency stabilized laser in	the 633 nm region	4.2×10 <sup>-11</sup>
Length	Gauge Blocks	From 0.1 mm up to 100 mm	0.02 μm
Measuring Instrument	(Interferometry method)	More than 100 mm up to 250 mm	(0.01+L/3500) μm
		More than 250 mm up to 400 mm	(0.02+L/3400) μm
		More than 400 mm up to 800 mm	(0.02+L/3200) μm
		More than 800 mm up to 1000 mm	(0.02+L/3100) μm
	Gauge Blocks	From 0.1 mm up to 100 mm	0.07 μm
	(Comparison method)	More than 100 mm up to 500 mm	(0.005+L/1800) μm
		More than 500 mm up to 1000 mm	(0.025+L/1800) μm
	End Gauges with flat ends (Comparison method)	From 0.1 mm up to 1010 mm	(0.2+L/650) μm
	Standard Scale	up to 300 mm	0.4 μm
		More than 300 mm up to 1000 mm	(0.2+L/1500) μm
	Calibration apparatus	up to 25 mm	0.3 μm
	for extensometers	More than 25 mm up to 50 mm	0.4 μm
		More than 50 mm up to 75 mm	0.5 μm
		More than 75 mm up to 100 mm	0.6 μm
	Extensometers	up to 5 mm	0.8 μm
		More than 5 mm up to 50 mm	2.4 μm
		More than 50 mm up to 600 mm	6.4 μm
Dimensional Measuring Instrument	One Dimensional Grating	From 97 nm up to 1000 nm	0.03 nm

#All Calibration Procedures are in-house procedures developed by this laboratory.

Note: The value in the Expanded Uncertainty column of 'Laser Wavelength' excludes sources of uncertainty attributed to a unit under test.

### <u>Laboratory's permanent facility/On-site Calibration: On-site Calibration</u> <u>Calibration and Measurement Capabilities</u>

Calibration Procedures# and			Expanded Uncertainty
Type of Instruments/Materials		Range	(Level of Confidence
to be	calibrated		Approximately 95 %)
Length	Extensometers	up to 5 mm	0.8 μm
Measuring Instrument		More than 5 mm up to 50 mm	2.4 μm
		More than 50 mm up to 600 mm	6.4 μm

General Field of Calibration: Mass

Date of Initial Accreditation of the Field: 1996-11-14

Laboratory's permanent facility/On-site Calibration: Laboratory's permanent facility

Calibration Procedures# and Type of Instruments/Materials to be calibrated				panded Unconfidence App	ertainty proximately 95 %)
		Range	One by one co		A method except One by one comparison
			Conventional mass	True mass	
Weight Weight and Deadweight		50 kg	0.30 g	12 μg/g	_
		More than 20 kg less than 50 kg	5.0 μg/g	12 μg/g	_
		20 kg	7.0 mg	11 μg/g	6.0 mg
		More than 10 kg less than 20 kg	$4.0~\mu g/g$	11 μg/g	_
		10 kg	3.0 mg	4.0 μg/g	2.1 mg
		More than 5 kg less than 10 kg	4.0 μg/g	4.0 μg/g	_
		5 kg	1.8 mg	4.0 μg/g	1.1 mg
		More than 3 kg less than 5 kg	$4.0~\mu \mathrm{g/g}$	4.0 μg/g	_
		3 kg	1.5 mg	4.0 μg/g	_
		More than 2 kg less than 3 kg	$4.0~\mu g/g$	4.0 μg/g	_
		2 kg	0.60 mg	4.0 μg/g	0.42 mg
		More than 1 kg less than 2 kg	$4.0~\mu g/g$	4.0 μg/g	_
		1 kg	0.20 mg	4.0 μg/g	0.16 mg
		More than 500 g less than 1 kg	$4.0~\mu g/g$	4.0 μg/g	_
		500 g	0.11 mg	4.0 μg/g	0.085 mg
		More than 300 g less than 500 g	$4.0~\mu g/g$	4.0 μg/g	_
		300 g	0.15 mg	4.0 μg/g	_
		More than 200 g less than 300 g	$4.0~\mu g/g$	4.0 μg/g	_
		200 g	0.060 mg	4.0 μg/g	0.035 mg
		More than 100 g less than 200 g	$4.0~\mu g/g$	4.0 μg/g	_
		100 g	0.030 mg	4.0 μg/g	0.019 mg
		More than 50 g less than 100 g	$4.0~\mu g/g$	4.0 μg/g	_
		50 g	0.020 mg	4.1 μg/g	0.010 mg
		More than 30 g less than 50 g	5.0 μg/g	4.7 μg/g	_
		30 g	0.026 mg	5.4 μg/g	_
		More than 20 g less than 30 g	$8.0~\mu \mathrm{g/g}$	9.0 μg/g	_
		20 g	0.015 mg	8.7 μg/g	0.0080 mg
		More than 10 g less than 20 g	9.0 μg/g	10 μg/g	_
		10 g	0.010 mg	15 μg/g	0.0060 mg
		More than 5 g less than 10 g	15 μg/g	17 μg/g	_
		5 g	0.0080 mg	25 μg/g	0.0050 mg
		More than 3 g less than 5 g	32 μg/g	35 μg/g	_
		3 g	0.013 mg	56 μg/g	_
		More than 2 g less than 3 g	25 μg/g	28 μg/g	_
		2 g	0.0060 mg	60 μg/g	0.0040 mg
		More than 1 g less than 2 g	40 μg/g	60 μg/g	_
		1 g	0.0050 mg	81 μg/g	0.0030 mg
		More than 500 mg less than 1 g	50 μg/g	90 μg/g	_
		500 mg	0.0040 mg	0.15 mg/g	0.0025 mg
		More than 200 mg less than 500 mg	80 μg/g	0.15 mg/g	_
		200 mg	0.0030 mg	0.17 mg/g	0.0020 mg

More than 100 mg less than 200 mg	0.16 mg/g	0.20 mg/g	_
100 mg	0.0025 mg	0.22 mg/g	0.0015 mg
More than 50 mg less than 100 mg	0.25 mg/g	0.30 mg/g	-
50 mg	0.0020 mg	0.30 mg/g	0.0012 mg
More than 20 mg less than 50 mg	0.45  mg/g	0.45 mg/g	-
20 mg	0.0016 mg	0.70 mg/g	0.0010 mg
More than 10 mg less than 20 mg	$0.90\mathrm{mg/g}$	0.90 mg/g	-
10 mg	0.0012 mg	1.1 mg/g	0.00080 mg
More than 5 mg less than 10 mg	1.6 mg/g	1.6 mg/g	-
5 mg	0.0011 mg	1.8 mg/g	0.00060 mg
More than 2 mg less than 5 mg	3.2 mg/g	3.2 mg/g	_
2 mg	0.0011 mg	4.3 mg/g	0.00060 mg
More than 1 mg less than 2 mg	$6.0\mathrm{mg/g}$	6.0 mg/g	-
1 mg	0.0011 mg	9.0 mg/g	0.00060 mg
0.8 mg	0.0016 mg	_	-
0.6 mg	0.0014 mg	_	-
0.5 mg	0.00080 mg	_	0.00040 mg
0.4 mg	0.0014 mg	_	-
0.2 mg	0.00080 mg	_	0.00040 mg
0.1 mg	0.00080 mg	_	0.00040 mg
0.05 mg	0.00080 mg	_	0.00040 mg

<sup>#</sup>All Calibration Procedures are in-house procedures developed by this laboratory.

# <u>Laboratory's permanent facility/On-site Calibration: Laboratory's permanent facility, On-site Calibration Calibration and Measurement Capabilities</u>

Calibration Procedures# and Type of Instruments/Materials		Range	Expanded Uncertainty (Level of Confidence Approximately 95 %)		
	to be calibrated		Permanent Laboratory	On-site Calibration	
Scale	Non-Automatic Electronic	More than 150 kg up to 600 kg	16 μg/g	16 μg/g	
	Weighing Instruments	More than 20 kg up to 150 kg	9.6 μg/g	9.6 μg/g	
		20 kg	3.0 μg/g	3.0 μg/g	
		More than 100 g less than 20 kg	1.1 μg/g	1.1 μg/g	
		100 g	0.97 μg/g	0.97 μg/g	
		More than 50 g less than 100 g	1.8 μg/g	1.8 μg/g	
		50 g	1.2 μg/g	1.2 μg/g	
		More than 20 g less than 50 g	2.8 μg/g	2.8 μg/g	
		More than 10 g up to 20 g	2.4 μg/g	2.4 μg/g	
		10 g	3.6 μg/g	3.6 μg/g	
		More than 5 g less than 10 g	8.8 μg/g	8.8 μg/g	
		5 g	5.9 μg/g	5.9 μg/g	
		More than 2 g less than 5 g	14 μg/g	14 μg/g	
		More than 1 g up to 2 g	12 μg/g	12 μg/g	
		1 g	18 μg/g	18 μg/g	
		More than 500 mg less than 1 g	45 μg/g	45 μg/g	
		500 mg	30 μg/g	30 μg/g	
		More than 200 mg less than 500 mg	71 μg/g	71 μg/g	

More than 100 mg up to 200 mg	59 μg/g	59 μg/g
100 mg	94 μg/g	94 μg/g
More than 50 mg less than 100 mg	0.22 mg/g	0.22 mg/g
50 mg	0.15 mg/g	0.15 mg/g
More than 20 mg less than 50 mg	0.36 mg/g	0.36 mg/g
More than 10 mg up to 20 mg	0.30 mg/g	0.30 mg/g
10 mg	0.47 mg/g	0.47 mg/g
More than 5 mg less than 10 mg	1.4 mg/g	1.4 mg/g
5 mg	0.71 mg/g	0.71 mg/g
More than 2 mg less than 5 mg	2.4 mg/g	2.4 mg/g
2 mg	1.8 mg/g	1.8 mg/g
1 mg	3.6 mg/g	3.6 mg/g

<sup>#</sup>All Calibration Procedures are in-house procedures developed by this laboratory.

General Field of Calibration: Temperature

Date of Initial Accreditation of the Field: 2014-11-13

Laboratory's permanent facility/On-site Calibration: Laboratory's permanent facility

Calibration and Measurement Capabilities

Type of	Calibration Procedures# and Type of Instruments/Materials to be calibrated  Range			Expanded Uncertainty (Level of Confidence Approximately 95 %)	
Contact Type	Liquid-in-glass Thermometer	From 0 °C up to 5	50 °C	0.04 °C	
Thermometer	Temperature sensors	110111 10 0 1000 1111111 1		0.03 °C	
	with display unit	with display unit (Comparison calibration)	100 ℃		0.04 °C
	(Companson Canoration)	More than 100 °C up to 200 °C		0.06 °C	
		More than 200 °C up	to 300 °C	0.08 °C	
		Equipped within temperature Controlled enclosures	From -40 °C up to 300 °C	0.4 °C	

<sup>#</sup>All Calibration Procedures are in-house procedures developed by this laboratory.

### <u>Laboratory's permanent facility/On-site Calibration: On-site Calibration Calibration and Measurement Capabilities</u>

Type of	alibration Procedures# and pe of Instruments/Materials to be calibrated  Range		Expanded Uncertainty (Level of Confidence Approximately 95 %)	
Contact Type Thermometer	Temperature sensors with display unit (Comparison calibration)	Equipped within temperature Controlled enclosures	From -40 °C up to 300 °C	0.4 °C

<sup>#</sup>All Calibration Procedures are in-house procedures developed by this laboratory.

General Field of Calibration: Angle

Date of Initial Accreditation of the Field: 2006-03-01

Laboratory's permanent facility/On-site Calibration: Laboratory's permanent facility

Calibration and Measurement Capabilities

Calibration Procedures# and Type of Instruments/Materials to be calibrated			Range	Expanded Uncertainty (Level of Confidence Approximately 95 %)
	Rotary Encoder		up to 225,000 points	0.05"
Angle Measuring Instrument	Rotary Encoder Calibration System (Self-calibration System)	0° to 360°		0.04"

<sup>#</sup>All Calibration Procedures are in-house procedures developed by this laboratory.

General Field of Calibration: Fluid flow

Date of Initial Accreditation of the Field: 2001-02-20

<u>Laboratory's permanent facility/On-site Calibration: Laboratory's permanent facility</u>

Type of Instru	rocedures# and ments/Materials alibrated	Range	Expanded Uncertainty (Level of Confidence Approximately 95 %)
Anemometers	Anemometers	From 0.05 m/s less than 0.30 m/s	0.019 m/s
	(Low air speed)	From 0.30 m/s less than 0.59 m/s	0.023 m/s
		From 0.59 m/s less than 0.88 m/s	0.028 m/s
		From 0.88 m/s less than 1.21 m/s	0.036 m/s
		From 1.21 m/s less than 1.50 m/s	0.042 m/s
	Anemometers (Medium air speed)	1.3 m/s	0.05 m/s
		More than 1.3 m/s up to 3 m/s	0.06 m/s
		More than 3 m/s up to 5 m/s	0.06 m/s
		More than 5 m/s up to 7 m/s	0.08 m/s
		More than 7 m/s up to 10 m/s	0.11 m/s
		More than 10 m/s up to 15 m/s	0.15 m/s
		More than 15 m/s up to 20 m/s	0.20 m/s
		More than 20 m/s up to 25 m/s	0.26 m/s
		More than 25 m/s up to 30 m/s	0.32 m/s
		More than 30 m/s up to 35 m/s	0.38 m/s
		More than 35 m/s up to 40 m/s	0.44 m/s

<sup>#</sup>All Calibration Procedures are in-house procedures developed by this laboratory.

General Field of Calibration: Acceleration

Date of Initial Accreditation of the Field: 2005-02-21

Laboratory's permanent facility/On-site Calibration: Laboratory's permanent facility

Calibration Procedures# and Type of Instruments/Materials		Range	Expanded Uncertainty (Level of Confidence
	o be calibrated		Approximately 95 %)
Accelerometer	Reference Accelerometer	0.5 Hz	1.3 %
	(Voltage sensitivity)	0.63 Hz	1.1 %
		0.8 Hz	1.1 %
		1 Hz	0.8 %
		1.25 Hz	0.7 %
		1.6 Hz	0.7 %
		2 Hz	0.7 %
		2.5 Hz	0.7 %
		3.15 Hz	0.7 %
		4 Hz	0.7 %
		5 Hz	0.7 %
		6.3 Hz	0.7 %
		8 Hz	0.7 %
		10 Hz	0.7 %
		12.5 Hz	0.7 %
		16 Hz	0.7 %
		20 Hz	0.5 %
		25 Hz	0.5 %
		31.5 Hz	0.5 %
		40 Hz	0.5 %
		50 Hz	0.5 %
		63 Hz	0.5 %
		80 Hz	0.5 %
		100 Hz	0.5 %
		125 Hz	0.5 %
		160 Hz	0.5 %
		200 Hz	0.5 %
		250 Hz	0.5 %
		315 Hz	0.5 %
		400 Hz	0.6 %
		500 Hz	0.5 %
		630 Hz	0.5 %
		800 Hz	0.5 %
		1 kHz	0.5 %
		1.25 kHz	0.5 %
		1.6 kHz	0.5 %
		2 kHz	0.6 %
		2.5 kHz	0.7 %
		3.15 kHz	0.7 %
		4 kHz	0.7 %
		5 kHz	0.7 %
		6.3 kHz	0.8 %
		8 kHz	0.8 %
		10 kHz	0.8 %
	Reference Accelerometer	20 Hz	0.6 %
	(Electric charge sensitivity)	25 Hz	0.6 %
		31.5 Hz	0.6 %
		40 Hz	0.6 %

50 Hz	0.6 %
63 Hz	0.6 %
80 Hz	0.6 %
100 Hz	0.6 %
125 Hz	0.6 %
160 Hz	0.6 %
200 Hz	0.6 %
250 Hz	0.7 %
315 Hz	0.7 %
400 Hz	0.7 %
500 Hz	0.6 %
630 Hz	0.6 %
800 Hz	0.6 %
1 kHz	0.6 %
1.25 kHz	0.6 %
1.6 kHz	0.6 %
2 kHz	0.7 %
2.5 kHz	0.8 %
3.15 kHz	0.8 %
4 kHz	0.8 %
5 kHz	0.8 %
6.3 kHz	0.9 %
8 kHz	0.9 %
10 kHz	0.9 %

<sup>#</sup>All Calibration Procedures are in-house procedures developed by this laboratory.

General Field of Calibration: Electricity (High Frequency) & Electromagnetic Fields
Date of Initial Accreditation of the Field: 1995-06-21
Laboratory's permanent facility/On-site Calibration: Laboratory's permanent facility
Calibration and Measurement Capabilities

Calibration Procedures# and				Expanded Uncertainty	
Type of Inst			Ran	ge	(Level of Confidence
Materials to be				1	Approximately 95 %)
Radio Frequency	RF Power		50 MHz	1 mW	0.45 %
Measuring	Source		10.14	1 mW	1.2 %
Equipments		From	10 MHz up to 12 GHz	From 10 pW less than 10 nW	1.8 %
	DED	G 11	103.61. 203.61	From 10 nW up to 100 mW	1.6 %
	RF Power	Coaxial 7 mm	10 MHz, 30 MHz, 50 MHz, 70 MHz,		
	Measuring Equipment	/ 111111	100 MHz, 300 MHz,		
	Equipment		500 MHz, 700 MHz,	1 mW	0.53%
			1 GHz, 2 GHz,		
			3 GHz, 4 GHz,		
			5 GHz, 6 GHz		
			7 GHz, 8 GHz	1 mW	0.76 %
			9 GHz, 10 GHz, 11 GHz, 12 GHz,	1 mW	0.88 %
			13 GHz	1 mW	0.92 %
			14 GHz, 15 GHz,		
			16 GHz, 17 GHz,	1 mW	1.4 %
			18 GHz		0.70/
				1 mW	0.7 %
			From 10 MHz	1 μW	0.9 %
			up to 200 MHz	From 10 nW up to 100 mW	1.6 %
				More than 100 mW up to 180 W	2.1 %
				1 mW	0.7 %
				1 μW	0.9 %
			More than 200 MHz	From 10 nW up to 100 mW	1.6 %
			Up to 400 MHz	More than 100 mW	
				up to 100 W	2.1 %
				1 mW	0.7 %
			More than 400 MHz	1 μW	0.9 %
			Up to 500 MHz	From 10 nW up to 100 mW	1.6 %
				More than 100 mW up to 60 W	2.1 %
				1 mW	0.7 %
			More than 500 MHz	1 μW	0.9 %
			up to 1 GHz	From 10 nW up to 100 mW	1.6 %
				More than 100 mW up to 40 W	2.1 %
				1 mW	0.7 %
			More than 1 GHz	1 μW	0.9 %
			up to 2 GHz	From 10 nW up to 100 mW	1.6 %
				More than 100 mW up to 20 W	2.1 %
			More than 2 GHz	1 mW	0.7 %
			up to 6 GHz	1 μW	0.9 %
				From 10 nW up to 100 mW 1 mW	1.6 %
			More than 6 GHz	1 mw 1 μW	1.0 %
			up to 12 GHz	From 10 nW up to 50 mW	1.6 %
			More than 12 GHz	1 mW	1.6 %
			up to 18 GHz	1 mw 1 μW	2.0 %
		Coaxial	10 MHz, 30 MHz,	·	
		2.9 mm	50 MHz, 70 MHz,	1 mW	1.1 %

<u> </u>	100 MHz 200 MH-	<u> </u>	
	100 MHz, 300 MHz, 500 MHz, 700 MHz,		
	1 GHz, 2 GHz,		
	3 GHz, 4 GHz,		
	5 GHz, 6 GHz,		
	7 GHz, 8 GHz, 9 GHz, 10 GHz,		
	11 GHz, 12 GHz		
	13 GHz, 14 GHz,		
	15 GHz, 16 GHz,		
	17 GHz, 18 GHz,		4.50/
	19 GHz, 20 GHz, 21 GHz, 22 GHz,	1 mW	1.5 %
	23 GHz, 24 GHz,		
	25 GHz		
	26 GHz, 27 GHz,		
	28 GHz, 29 GHz,		
	30 GHz, 31 GHz, 32 GHz, 33 GHz,		
	34 GHz, 35 GHz,	1 mW	3.1 %
	36 GHz, 37 GHz,		
	38 GHz, 39 GHz,		
	40 GHz From 10 MHz		
	up to 12 GHz	1 mW	1.6 %
	More than 12 GHz up to 25 GHz	1 mW	2.3 %
	More than 25 GHz up to 40 GHz	1 mW	4.7 %
RF Voltage	From 10 MHz up to 50 MHz	From 0.2 V up to 0.9 V	0.50 %
Measuring Equipment	More than 50 MHz up to 500 MHz	From 0.2 V up to 0.9 V	0.80 %
	More than 500 MHz up to 1000 MHz	From 0.2 V up to 0.9 V	1.2 %
Attenuator		From 0 dB up to 40 dB	0.011 dB
$(50 \Omega)$	From 10 MHz	More than 40 dB up to 60 dB	$0.014~\mathrm{dB}$
	up to 1 GHz	More than 60 dB up to 80 dB	0.020 dB
		More than 80 dB up to 100 dB	0.031 dB
		From 0 dB up to 40 dB	0.016 dB
	More than 1 GHz	More than 40 dB up to 60 dB	0.018 dB
	up to 12 GHz	More than 60 dB up to 80 dB	0.028 dB
		More than 80 dB up to 100 dB	0.037 dB
		From 0 dB up to 40 dB	0.022 dB
	Maria thai: 12 CII-	More than 40 dB up to 60 dB	0.022 dB
	More than 12 GHz up to 18 GHz	More than 60 dB up to 80 dB	0.024 dB
	ap to to other	More than 80 dB up to 100 dB	0.039 dB 0.046 dB
	More than 18 GHz up to 40 GHz	From 0 dB up to 40 dB	0.028 dB
A ++ a + *	ար w <del>1</del> 0 OПZ	More than 40 dB up to 60 dB	0.054 dB
Attenuation Measuring		From 0 dB up to 40 dB	0.007 dB
Equipment	10 MHz, 30 MHz, 1 GHz	More than 40 dB up to 60 dB	0.010 dB
		More than 60 dB up to 80 dB	0.016 dB
		More than 80 dB up to 100 dB	0.024 dB
	12 GHz	From 0 dB up to 40 dB	0.008 dB

		More than 40 dB up to 60 dB	0.011 dB
		More than 60 dB up to 80 dB	$0.027~\mathrm{dB}$
		More than 80 dB up to 100 dB	$0.034~\mathrm{dB}$
		From 0 dB up to 40 dB	0.013 dB
	18 GHz	More than 40 dB up to 60 dB	0.016 dB
	16 ОПХ	More than 60 dB up to 80 dB	$0.070~\mathrm{dB}$
		More than 80 dB up to 100 dB	0.058 dB
	20 GHz, 25 GHz, 30 GHz,	From 0 dB up to 40 dB	0.020 dB
	35 GHz, 40 GHz	More than 40 dB up to 60 dB	0.047 dB
	From 10 MHz up to 1 GHz	From 0 dB up to 40 dB	0.011 dB
		More than 40 dB up to 60 dB	0.014 dB
		More than 60 dB up to 80 dB	0.020 dB
		More than 80 dB up to 100 dB	0.031 dB
	More than 1 GHz up to 12 GHz	From 0 dB up to 40 dB	0.016 dB
		More than 40 dB up to 60 dB	0.018 dB
		More than 60 dB up to 80 dB	0.028 dB
		More than 80 dB up to 100 dB	0.037 dB
		From 0 dB up to 40 dB	0.022 dB
	More than 12 GHz	More than 40 dB up to 60 dB	0.024 dB
	up to 18 GHz	More than 60 dB up to 80 dB	0.039 dB
		More than 80 dB up to 100 dB	0.046 dB
	More than 18 GHz	From 0 dB up to 40 dB	0.028 dB
	up to 40 GHz	More than 40 dB up to 60 dB	0.054 dB

Calibration Procedures# and Type of Instruments/Materials to be calibrated		Range		nge	Expanded Uncertainty (Level of Confidence Approximately 95 %)
Radio Frequency Measuring Equipments	RF Impedance	Type-N 50 Ω Male	Reflection Coefficient  Sii  up to 0.1	From 9 kHz less than 40 MHz From 40 MHz up to 4 GHz More than 4 GHz up to 8 GHz	Amplitude Um: 0.0015~0.0033  (Amplitude step:0.0001)  Phase [°]: arcsin (Um/ Reflection Coefficient )  Amplitude Um: 0.0031~0.0038  (Amplitude step:0.0001)  Phase [°]: arcsin (Um/ Reflection Coefficient )  Amplitude Um: 0.0036~0.0041  (Amplitude step:0.0001)  Phase [°]: arcsin (Um/ Reflection Coefficient )
				More than 8 GHz up to 14 GHz More than 14 GHz up to 18 GHz	Amplitude Um: 0.0040~0.0054  (Amplitude step:0.0001)  Phase [°]: arcsin (Um/ Reflection Coefficient )  Amplitude Um: 0.0049~0.0068  (Amplitude step:0.0001)
			Reflection Coefficient  Sii	From 9 kHz less than 40 MHz	Phase [°]: arcsin (Um/ Reflection Coefficient )   Amplitude Um: 0.0022~0.0037   (Amplitude step:0.0001)   Phase [°]: arcsin (Um/ Reflection Coefficient )

,			
	up to 0.3	From 40 MHz	Amplitude Um: 0.0036~0.0046
		up to 4 GHz	(Amplitude step:0.0001)
			Phase [°]: arcsin (Um/ Reflection Coefficient )
		More than 4 GHz	Amplitude Um: 0.0042~0.0047
		up to 8 GHz	(Amplitude step:0.0001)
			Phase [°]: arcsin (Um/ Reflection Coefficient )
		More than 8 GHz	Amplitude Um: 0.0048~0.0060
		up to 14 GHz	(Amplitude step:0.0001)
			Phase [°]: arcsin (Um/ Reflection Coefficient )
			Amplitude Um: 0.0054~0.0074
		up to 18 GHz	(Amplitude step:0.0001)
	D (1 .:	E 0111	Phase [°]: arcsin (Um/ Reflection Coefficient )
	Reflection Coefficient	From 9 kHz less than 40 MHz	Amplitude Um: 0.0028~0.0042 (Amplitude step:0.0001)
	Sii	less than 40 MHz	Phase [°]: arcsin (Um/ Reflection Coefficient )
	up to $0.5$	From 40 MHz	Amplitude Um: 0.0041~0.0056
	•	up to 4 GHz	(Amplitude step:0.0001)
		•	Phase [°]: arcsin (Um/ Reflection Coefficient )
		More than 4 GHz	Amplitude Um: 0.0049~0.0058
		up to 8 GHz	(Amplitude step:0.0001)
			Phase [°]: arcsin (Um/ Reflection Coefficient )
		More than 8 GHz	Amplitude Um: 0.0057~0.0076
		up to 14 GHz	(Amplitude step:0.0001)
		M 41 14 CII-	Phase [°]: arcsin (Um/ Reflection Coefficient )
		up to 18 GHz	Amplitude Um: 0.0065~0.0093 (Amplitude step:0.0001)
		up to 16 GHZ	Phase [°]: arcsin (Um/ Reflection Coefficient )
	Reflection	From 9 kHz	Amplitude Um: 0.0048~0.0075
	Coefficient	less than 40 MHz	(Amplitude step:0.0001)
	Sii		Phase [°]: arcsin (Um/ Reflection Coefficient )
	up to 1.0	From 40 MHz	Amplitude Um: 0.0072~0.011
		up to 4 GHz	(Amplitude step:0.0001)
		)	Phase [°]: arcsin (Um/ Reflection Coefficient )
		More than 4 GHz up to 8 GHz	Amplitude Um: 0.0084~0.011 (Amplitude step:0.0001)
		up to 8 GHz	Phase [°]: arcsin (Um/ Reflection Coefficient )
		More than 8 GHz	Amplitude Um: 0.011~0.015
		up to 14 GHz	(Amplitude step:0.001)
		•	Phase [°]: arcsin (Um/ Reflection Coefficient )
		More than 14 GHz	Amplitude Um: 0.013~0.020
		up to 18 GHz	(Amplitude step:0.001)
		•	Phase [°]: arcsin (Um/ Reflection Coefficient )
Type-N	Reflection	From 9 kHz	Amplitude Um: 0.0014~0.0033
50 Ω	Coefficient	less than 40 MHz	(Amplitude step:0.0001)
Female	Sii		Phase [°]: arcsin (Um/ Reflection Coefficient )
	up to 0.1	From 40 MHz	Amplitude Um: 0.0031~0.0039
		up to 4 GHz	(Amplitude step:0.0001)
		_	Phase [°]: arcsin (Um/ Reflection Coefficient )
		More than 4 GHz	Amplitude Um: 0.0036~0.0045
		up to 8 GHz	(Amplitude step:0.0001)
			\ 1 1 . ***-/

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		Phase [°]: arcsin (Um/ Reflection Coefficient )
	More than 8 GHz	Amplitude Um: 0.0040~0.0051
	up to 14 GHz	(Amplitude step:0.0001)
		Phase [°]: arcsin (Um/ Reflection Coefficient )
		Amplitude Um: 0.0045~0.0057
	up to 18 GHz	(Amplitude step:0.0001)
		Phase [°]: arcsin (Um/ Reflection Coefficient )
Reflection	From 9 kHz	Amplitude Um: 0.0021~0.0037
Coefficient	less than 40 MHz	(Amplitude step:0.0001)
S <i>ii</i>   up to 0.3		Phase [°]: arcsin (Um/ Reflection Coefficient )
up to 0.5	From 40 MHz	Amplitude Um: 0.0035~0.0044
	up to 4 GHz	(Amplitude step:0.0001)
		Phase [°]: arcsin (Um/ Reflection Coefficient )
	More than 4 GHz up to 8 GHz	Amplitude Um: 0.0043~0.0049 (Amplitude step:0.0001)
	up to 8 GHz	Phase [°]: arcsin (Um/ Reflection Coefficient )
	More than 8 GHz	Amplitude Um: 0.0045~0.0058
	up to 14 GHz	(Amplitude step:0.0001)
	_	Phase [°]: arcsin (Um/ Reflection Coefficient )
	More than 14 GHz	Amplitude Um: 0.0050~0.0068
	up to 18 GHz	(Amplitude step:0.0001)
Reflection	From 9 kHz	Phase [°]: arcsin (Um/ Reflection Coefficient ) Amplitude Um: 0.0027~0.0042
Coefficient	less than 40 MHz	(Amplitude step:0.0001)
Sii	1000 111111	Phase [°]: arcsin (Um/ Reflection Coefficient )
up to 0.5	From 40 MHz	Amplitude Um: 0.0040~0.0054
	up to 4 GHz	(Amplitude step:0.0001)
	_	Phase [°]: arcsin (Um/ Reflection Coefficient )
	More than 4 GHz	Amplitude Um: 0.0050~0.0060
	up to 8 GHz	(Amplitude step:0.0001)
		Phase [°]: arcsin (Um/ Reflection Coefficient )
	More than 8 GHz	Amplitude Um: 0.0051~0.0070
	up to 14 GHz	(Amplitude step:0.0001)
		Phase [°]: arcsin (Um/ Reflection Coefficient )
		Amplitude Um: 0.0056~0.0084
	up to 18 GHz	(Amplitude step:0.0001)
		Phase [°]: arcsin (Um/ Reflection Coefficient )
Reflection	From 9 kHz	Amplitude Um: 0.0046~0.0075
Coefficient  Sii	less than 40 MHz	(Amplitude step:0.0001)
up to 1.0	- 403.57	Phase [°]: arcsin (Um/ Reflection Coefficient )
1	From 40 MHz up to 4 GHz	Amplitude Um: 0.0069~0.010 (Amplitude step:0.0001)
	up 10 4 G112	Phase [°]: arcsin (Um/ Reflection Coefficient )
	More than 4 GHz	Amplitude Um: 0.0085~0.011
	up to 8 GHz	(Amplitude step:0.0001)
		Phase [°]: arcsin (Um/ Reflection Coefficient )
	More than 8 GHz	Amplitude Um: 0.0084~0.013
	up to 14 GHz	(Amplitude step:0.0001)
		Phase [°]: arcsin (Um/ Reflection Coefficient )

		More than 14 GHz	Amplitude Um: 0.011~0.017
		up to 18 GHz	(Amplitude step:0.001)
			Phase [°]: arcsin (Um/ Reflection Coefficient )

Calibration Procedures# and Type of Instruments/Materials to be calibrated		Ç			Expanded Uncertainty (Level of Confidence Approximately 95 %)
Laser Power	Optical Beam	am 405 nm Band		From 10 µW less than 50 µW	0.9 %
	Power Meter			From 50 μW less than 100 μW	0.36 %
Equipments				From 100 µW up to 5 mW	0.29 %
	-	488 nm B	and	From 10 μW less than 50 μW	0.9 %
		515 nm B	and	From 50 μW less than 100 μW	0.36 %
				From 100 µW up to 200 mW	0.29 %
	-	633 nm B	and	From 10 μW less than 50 μW	0.9 %
				From 50 μW less than 100 μW	0.36 %
				From 100 µW up to 10 mW	0.29 %
		660 nm B	and	From 10 μW less than 50 μW	0.9 %
				From 50 μW less than 100 μW	0.36 %
				From 100 µW up to 7 mW	0.29 %
	-	780 nm B	and	From 10 μW less than 50 μW	0.9 %
				From 50 μW less than 100 μW	0.36 %
				From 100 µW up to 10 mW	0.29 %
		850 nm B		From 10 μW less than 50 μW	0.9 %
	1310 nm	1310 nm Band From 50 μW less than 1	From 50 $\mu W$ less than 100 $\mu W$	0.36 %	
				From 100 µW up to 3 mW	0.29 %
		1047 nm I	Band	From 10 µW less than 50 µW	0.9 %
				From 50 $\mu W$ less than 100 $\mu W$	0.36 %
			From 10	From 100 µW up to 10 mW	0.29 %
		1064 nm I	Band	From 10 $\mu W$ less than 50 $\mu W$	0.9 %
				From 50 $\mu W$ less than 100 $\mu W$	0.36 %
				From 100 $\mu$ W up to 10 mW	0.29 %
		1550 nm I	Band	From 10 $\mu W$ less than 50 $\mu W$	0.9 %
				From 50 $\mu W$ less than 100 $\mu W$	0.36 %
				From 100 µW up to 5 mW	0.29 %
	Optical Fiber	850 nm B	and	From 10 µW less than 50 µW	1.0 %
	Power Meter			From 50 $\mu W$ less than 100 $\mu W$	0.5 %
				From 100 µW up to 200 µW	0.35 %
		1310 nm I		From 10 $\mu W$ less than 50 $\mu W$	1.0 %
		From 1520 Up to 1630		From 50 $\mu W$ less than 100 $\mu W$	0.5 %
		Op to 1030	J 1IIII	From 100 µW up to 10 mW	0.35 %
		Photodiode Type	1310 nm	1 mW	0.36 %

			100W	0.41 %
			100 μW	
			10 μW	0.41 %
			1 μW	0.42 %
			100 nW	0.42 %
			10 nW	0.43 %
			1 nW	0.43 %
			$100\mathrm{pW}$	0.48 %
			10 pW	0.62 %
			1 pW	1.9 %
		From 1280 nm	1 mW	0.36 %
		up to 1340 nm	100 μW	0.42 %
		-	10 μW	0.42 %
			·	
		-	1 μW	0.42 %
		-	100 nW	0.43 %
			10 nW	0.45 %
			1 nW	0.45 %
			100 pW	0.50 %
			10 pW	0.65 %
			1 pW	1.9 %
		1550 nm	1 mW	0.36 %
			100 μW	0.39 %
			10 μW	0.39 %
			1 μW	0.39 %
		_	100 nW	0.39 %
			10 nW	0.40 %
			1 nW	0.40 %
			100 pW	0.45 %
			10 pW	0.50 % 1.5 %
		E 1520	1 pW 1 mW	0.36 %
		From 1520 nm up to 1630 nm	100 μW	0.42 %
			10 μW	0.42 %
			1 μW	0.43 %
			100 nW	0.43 %
			10 nW	0.43 %
			1 nW	0.43 %
		<b> </b>	100 pW	0.48 %
		[	10 pW	0.54 %
			1 pW	1.5 %
Photodiode	Optical Fiber Power	1310 nm	-10 dB	0.0091 dB
Sensor	Response Linearity	<u> </u>	-20 dB	0.0093 dB
	(in dB unit relative		-30 dB	0.0096 dB
	to 0 dBm (1 mW))		-40 dB	0.0099 dB
			-50 dB	0.011 dB
			-60 dB -70 dB	0.011 dB 0.014 dB
			-80 dB	0.014 dB 0.023 dB
			-90 dB	0.023 dB 0.078 dB
		+	-10 dB	0.0093 dB
1		<u> </u>	10 00	0.00/J <b>u</b> D

From 1280 nm	-20 dB	0.0098 dB
up to 1340 nm	-30 dB	0.011 dB
1	-40 dB	0.011 dB
	-50 dB	0.012 dB
	-60 dB	0.013 dB
	-70 dB	0.016 dB
	-80 dB	0.024 dB
	-90 dB	0.079 dB
1550 nm	-10 dB	0.0056 dB
	-20 dB	0.0057 dB
	-30 dB	0.0058 dB
	-40 dB	0.0059 dB
	-50 dB	0.0061 dB
	-60 dB	0.0070 dB
	-70 dB	0.013 dB
	-80 dB	0.017 dB
	-90 dB	0.062 dB
From 1520 nm	-10 dB	0.011 dB
up to 1630 nm	-20 dB	0.011 dB
	-30 dB	0.011 dB
	-40 dB	0.011 dB
	-50 dB	0.011 dB
	-60 dB	0.011 dB
	-70 dB	0.015 dB
	-80 dB	0.018 dB
	-90 dB	0.063 dB

General Field of Calibration: Force
Date of Initial Accreditation of the Field: 2010-09-03
Laboratory's permanent facility/On-site Calibration: On-site Calibration

Calibration and Measurement Capabilities

Calibration Procedures and Type of Instruments/Materials to be calibrated		Range		Expanded Uncertainty (Level of Confidence Approximately 95 %)
Uniaxial Testing Machines	<u> </u>	Compression	From 0.1 N up to 5 MN	0.20 %
	(ISO 7500-1)#	Tension	From 0.1 N up to 100 kN	0.20 %
	According to ASTM E4	Compression	From 0.1 N up to 2000 kN	0.40 %
		Tension	From 0.1 N up to 100 kN	0.30 %

# JIS B 7721:2018, ISO 7500-1: 2015

General Field of Calibration: Acoustics & Ultrasound Date of Initial Accreditation of the Field: 2005-02-21

Laboratory's permanent facility/On-site Calibration: Laboratory's permanent facility

Calibration Procedures# and Type of Instruments/Materials to be calibrated		Range	Expanded Uncertainty (Level of Confidence Approximately 95 %)
Acoustic Measuring		From 20 Hz less than 25 Hz	0.11 dB
Equipment etc.	(Pressure Sensitivity Level Type LS1 Microphone)	From 25 Hz less than 63 Hz	0.09 dB
	LS1 Wicrophone)	From 63 Hz up to 4000 Hz	0.08 dB
		More than 4000 Hz up to 8000 Hz	0.14 dB
		More than 8000 Hz up to 10000 Hz	0.23 dB
		More than 10000 Hz up to 12500 Hz	0.38 dB
	Measurement Microphone	20 Hz (Exact Frequency)	0.20 dB
	(Pressure Sensitivity Level Type	From 20 Hz less than 31.5 Hz	0.18 dB
	LS2 Microphone)	From 31.5 Hz less than 63 Hz	0.13 dB
		From 63 Hz less than 125 Hz	0.11 dB
		From 125 Hz less than 500 Hz	0.10 dB
		From 500 Hz up to 8000 Hz	0.10 dB
		More than 8000 Hz up to 12500 Hz	0.12 dB
		More than 12500 Hz up to 20000 Hz	0.29 dB
	Measurement Microphone	From 20 Hz up to 4000 Hz	0.3 dB
	(Free-field Sensitivity Level Type	More than 4000 Hz up to 8000 Hz	0.4 dB
	LS1 or WS1 Microphone)	More than 8000 Hz up to 10000 Hz	0.5 dB
		More than 10000 Hz up to 12500 Hz	0.6 dB
	Measurement Microphone	From 20 Hz up to 4000 Hz	0.3 dB
	(Free-Field Sensitivity Level Type LS2 or WS2 Microphone)	More than 4000 Hz up to 9000 Hz	0.4 dB
	L32 of w32 Microphone)	More than 9000 Hz up to 16000 Hz	0.6 dB
		More than 16000 Hz up to 20000 Hz	1.0 dB
	Sound Level Meter	From 20 Hz up to 50 Hz	0.4 dB
	(Free-Field Response Level Type LS1 Microphone)	More than 50 Hz up to 3150 Hz	0.3 dB
	LS1 Wicrophone)	More than 3150 Hz up to 8000 Hz	0.5 dB
		More than 8000 Hz up to 12500 Hz	0.7 dB
	Sound Level Meter	From 20 Hz up to 50 Hz	0.5 dB
	(Free-Field Response Level Type LS 2 Microphone)	More than 50 Hz up to 3150 Hz	0.3 dB
	L3 2 Microphone)	More than 3150 Hz up to 12500 Hz	0.6 dB
		More than 12500 Hz up to 20000 Hz	0.9 dB
	Sound Level Meter	From 20 Hz up to 50 Hz	0.5 dB
	(Free-Field Response Level Type LS 2 Microphone) (Exact	More than 50 Hz up to 4000 Hz	0.4 dB
	Frequency)	More than 4000 Hz up to 10000 Hz	0.5 dB
		More than 10000 Hz up to 20000 Hz	0.7 dB
	Sound Calibrator	250 Hz	0.09 dB
	(Sound Pressure Level Type LS1 or WS1 Microphone)	1000 Hz	0.09 dB
	Sound Calibrator	250 Hz	0.11 dB
	(Sound Pressure Level Type LS2 or WS2 Microphone)	1000 Hz	0.11 dB
	Sound Calibrator with Multiple	31.5 Hz	0.14dB

Calibration Procedures# and Type of Instruments/Materials to be calibrated		Range		Expanded Uncertainty (Level of Confidence Approximately 95 %)	
	Frequencies	63 Hz		0.12 dB	
	(Sound Pressure Level Type		125 Hz	0.12 dB	
	LS2 or WS2 Microphone)		250 Hz	0.12 dB	
			500 Hz	0.12 dB	
			1000 Hz	0.12 dB	
			2000 Hz	0.12 dB	
		4000 Hz		0.12 dB	
			8000 Hz	(Level of Confidence Approximately 95 %) 0.12 dB 0.12 dB 0.12 dB 0.12 dB 0.12 dB 0.12 dB	
		12500 Hz		0.13 dB	
			16000 Hz	0.32 dB	
	Audiometers (WS1 Microphone)  Audiometers (WS2 Microphone)		From 125 Hz up to 4000 Hz	0.6 dB	
		Pressure Level	More than 4000 Hz up to 8000 Hz	0.6 dB	
			From 125 Hz up to 4000 Hz	0.7 dB	
			More than 4000 Hz up to 8000 Hz	0.9 dB	

## <u>Laboratory's permanent facility/On-site Calibration: On-site Calibration Calibration and Measurement Capabilities</u>

T	Range	Expanded Uncertainty (Level of Confidence Approximately 95 %)	
Acoustic Measuring	Sound Calibrator	250 Hz	0.13 dB
Equipment etc.	(Sound Pressure Level Type LS1 or WS1 Microphone)	1000 Hz	0.13 dB
	Sound Calibrator	250 Hz	0.14 dB
	(Sound Pressure Level Type LS2 or WS2 Microphone)	1000 Hz	0.14 dB

General Field of Calibration: Radiation & Radioactivity & Neutron

Date of Initial Accreditation of the Field: 1998-11-16

<u>Laboratory's permanent facility/On-site Calibration: Laboratory's permanent facility</u>

Calibration Procedures# and Type of Instruments/Materials to be calibrated		Expanded Uncertainty Range (Level of Confidence Approximately 95 %)				
X-ray		Range of Energy: From 10 keV (1.6 fJ) up to 30 keV (4.8 fJ)				
Measuring Equipment	Measuring Equipment (Soft X-Ray)	Exposure From 100 nC/kg up to 30 mC/kg		3.3 %		
Equipment	(Soft A-Ray)	Evenogue Data	From 2.5 $\mu$ C/(kg·h) less than 6 $\mu$ C/(kg·h)	3.5 %		
		Exposure Rate	From 6 $\mu$ C/(kg·h) up to 100 mC/(kg·h)	3.3 %		
		Air Absorbed Dose	From 3.5 $\mu$ Gy up to 1.0 Gy	3.3 %		
		Air Absorbed Dose	From 90 $\mu$ Gy/h less than 210 $\mu$ Gy/h	3.5 %		
		Rate	From 210 $\mu$ Gy/h up to 3.5 Gy/h	3.3 %		
		Air Kerma	From 3.5 $\mu$ Gy up to 1.0 Gy	3.3 %		
		Air Kerma Rate	From 90 $\mu$ Gy/h less than 210 $\mu$ Gy/h	3.5 %		
		Air Kerma Rate	From 210 $\mu$ Gy/h up to 3.5 Gy/h	3.3 %		
		Dose Equivalent	From 1 $\mu Sv$ up to 100 mSv	5.2 %		
		Dose Equivalent Rate From 25 μSv/h up to 500 mSv/h		5.5 %		
	Exposure	Range of Energy: From 30 keV (4.8 fJ) up to 200 keV (32 fJ)				
	Measuring Equipment Medium Hard X-Ray)	Exposure	From 100 nC/kg up to 60 mC/kg	3.3 %		
	(Wicdiam Hard X Ray)	Exposure Rate	From 100 nC/(kg·h) less than 6 $\mu$ C/(kg·h)	3.7 %		
			From 6 $\mu$ C/(kg·h) up to 160 mC/(kg·h)	3.3 %		
		Air Absorbed Dose	From 3.5 $\mu$ Gy up to 1.8 Gy	3.3 %		
		Air Absorbed Dose	From 3.5 $\mu$ Gy/h less than 210 $\mu$ Gy/h	3.7 %		
		Rate	From 210 $\mu$ Gy/h up to 5.2 Gy/h	3.3 %		
		Air Kerma	From 3.5 $\mu$ Gy up to 1.8 Gy	3.3 %		
		Air Kerma Rate	From 3.5 $\mu$ Gy/h less than 210 $\mu$ Gy/h	3.7 %		
		Air Kerma Kale	From 210 $\mu$ Gy/h up to 5.2 Gy/h	3.3 %		
		Dose Equivalent	From 3 $\mu Sv$ up to 200 mSv	5.2 %		
		Dose Equivalent Rate	From 3 $\mu$ Sv/h up to 1 Sv/h	5.5 %		

<sup>#</sup>All Calibration Procedures are in-house procedures developed by this laboratory.

Calibration Procedures# and Type of Instruments/Materials to be calibrated		Range		Expanded Uncertainty (Level of Confidence Approximately 95 %)	
γ-ray	Exposure	Exposure	From 52 nC/kg less than 880 nC/kg	4.2 %	
Measuring Equipment	Measuring Equipment (137Cs)		From 880 nC/kg up to 250 µC/kg	4.0 %	
Equipment	( CS)		From 52 nC/(kg·h) less than 800 nC/(kg·h)	4.4 %	
		Exposure Rate	From 800 nC/(kg·h) less than 16 $\mu$ C/(kg·h)	4.1 %	
			Range       (Level of Conf Approximately         From 52 nC/kg less than 880 nC/kg       4.2 %         From 880 nC/kg up to 250 μC/kg       4.0 %         From 52 nC/(kg·h) less than 800 nC/(kg·h)       4.4 %         From 800 nC/(kg·h) less than 16 μC/(kg·h)       4.1 %         From 16 μC/(kg·h) up to 800 μC/(kg·h)       3.8 %         From 2 μGy less than 28 μGy       4.2 %         From 28 μGy up to 8 mGy       4.0 %         From 2 μGy/h less than 25 μGy/h       4.4 %		
		Air Absorbed Dose	From 2 μGy less than 28 μGy	4.2 %	
		Air Absorbed Dose	From 28 μGy up to 8 mGy	4.0 %	
		Air Absorbed Dose Rate	From 2 μGy/h less than 25 μGy/h	4.4 %	
			From 25 $\mu$ Gy/h less than 500 $\mu$ Gy/h	4.1 %	
			From 500 $\mu$ Gy/h up to 25 mGy/h	3.8 %	
		Air Kerma	From 2 μGy less than 28 μGy	4.2 %	
		All Kellia	From 28 μGy up to 8 mGy	4.0 %	
		Air Kerma Rate	From 2 $\mu$ Gy/h less than 25 $\mu$ Gy/h	4.4 %	
			From 25 $\mu$ Gy/h less than 500 $\mu$ Gy/h	4.1 %	
			From 500 $\mu$ Gy/h up to 25 mGy/h	3.8 %	
		Dose Equivalent	From 2 $\mu$ Sv less than 35 $\mu$ Sv	5.8 %	
			From 35 µSv up to 10 mSv	5.6 %	
		Dose Equivalent Rate	From 2 $\mu Sv/h$ less than 30 $\mu Sv/h$	5.9 %	
			From 30 $\mu Sv/h$ less than 600 $\mu Sv/h$	5.7 %	
		Tate	From 600 $\mu Sv/h$ up to 30 mSv/h	5.5 %	

<sup>#</sup>All Calibration Procedures are in-house procedures developed by this laboratory.

General Field of Calibration: Hardness

<u>Date of Initial Accreditation of the Field: 2006-03-01</u>

<u>Laboratory's permanent facility/On-site Calibration:</u> <u>Laboratory's permanent facility, On-site Calibration</u>

Calibration and Measurement Capabilities

Calibration Procedures# and Type of Instruments/Materials to be calibrated		Range		Expanded Uncertainty (Level of Confidence Approximately 95 %)	
to be ca	alibrated			Permanent Laboratory	
Rockwell Hardness		From 20 HRC up to 25 HRC		0.55 HRC	0.55 HRC
Testing Machines,	Testing Machines	More than 25 HRC up to 35 HRC		0.55 HRC	0.55 HRC
etc.		More than	35 HRC up to 45 HRC	0.55 HRC	0.55 HRC
		More than	45 HRC up to 55 HRC	0.50 HRC	0.50 HRC
		More than	55 HRC up to 65 HRC	0.40 HRC	0.40 HRC
Vickers Hardness	Vickers Hardness		Test force 0.9807 N	16 %	16 %
Testing Machines, etc.	Testing Machines		Test force 4.903 N	7.0 %	7.0 %
etc.		200 HV*	Test force 9.807 N	5.1 %	5.1 %
			Test force 49.03 N	2.7 %	2.7 %
			Test force 98.07 N	2.6 %	2.6 %
			Test force 0.9807 N	22 %	22 %
			Test force 4.903 N	10 %	10 %
		400 HV*	Test force 9.807 N	7.0 %	7.0 %
			Test force 98.07 N	2.6 %	2.6 %
			Test force 294.2 N	2.5 %	2.5 %
		700 HV*	Test force 0.9807 N	30 %	30 %
			Test force 4.903 N	15 %	15 %
			Test force 9.807 N	9.1 %	9.1 %
			Test force 98.07 N	5.0 %	5.0 %
		Test force 294.2 N		2.7 %	2.7 %
				a) <i>d</i> ≦220 μm	a) <i>d</i> ≦220 μm
				576/d %	576/d %
			00 HV up to 800 HV * marked points above.	b) <i>d</i> >220 μm	b) <i>d</i> >220 μm
			force from 0.9807 N	994/ <i>d</i> %	994/d %
		up to 294.2 N)		Where: <i>d</i> is the length of a diagonal line of	Where: <i>d</i> is the length of a diagonal line of
Brinell Hardness	Brinell Hardness	200	) HBW 10/3000	the indentation (µm) 6 HBW	the indentation (µm) 6 HBW
Testing Machine,	Testing Machines			6 HBW	6 HBW
etc.	_	350 HBW 10/3000 500 HBW 10/3000 200 HBW 5/750 350 HBW 5/750 500 HBW 5/750		10 HBW	10 HBW
				7 HBW	7 HBW
				7 HBW	7 HBW
				10 HBW	10 HBW
		90 HBW 10/500		3 HBW	3 HBW
				3 HBW	3 HBW
		100 HBW 10/500 100 HBW 10/1000 200 HBW 10/1000 * Hardness Reference Blocks : Polish		4 HBW	4 HBW
				4 HBW	4 HBW
				L	711011
		Tardiless	Reference Diocks . Polis		

General Field of Calibration: Humidity

Date of Initial Accreditation of the Field: 2006-03-01

Laboratory's permanent facility/On-site Calibration: Laboratory's permanent facility, On-site Calibration

Calibration Procedures# and Type of Instruments/Materials to be calibrated		R	lange	Expanded Uncertainty (Level of Confidence Approximately 95 %)  Permanent On-site	
				Laboratory	Calibration
Humidity Dew point		Frost point from	-30 °C up to -10 °C	0.17 °C	-
Measuring Instrument,	hygrometers	Dew point from	1 -10 °C up to 50 °C	0.10 °C	-
etc.		Dew point more t	han 50 °C up to 85 °C	Dew point 0.11 °C	-
			Relative humidity from 5 % up to 40 %	Relative humidity 0.5 %	1
		Temperature Point From 5 °C up to 60 °C	Relative humidity more than 40 % up to 70 %	Relative humidity 0.7 %	-
			Relative humidity more than 70 % up to 98 %	Relative humidity 1.0 %	-
	Aspirated psychrometers	Temperature Point From 5 °C up to 25 °C (Dew point is from -10 °C up to 50 °C)	Relative humidity from 10 % up to 98 %	Relative humidity 1.0 %	-
	Electronic hygrometers	Temperature Point From 5 °C up to 60 °C (Dew point (Frost point) is from -30 °C up to 50 °C)	Relative humidity from 5 % up to 40 %	Relative humidity 0.5 %	-
			Relative humidity more than 40 % up to 70 %	Relative humidity 0.7 %	-
			Relative humidity more than 70 % up to 98 %	Relative humidity 1.0 %	1
		Temperature Point From 50 °C up to 95 °C (Dew point is	Relative humidity from 5 % up to 35 % Relative humidity More than 35 % up to 54 %	Relative humidity 1.6 %  Relative humidity 2.0 %	-
		from 15 °C up to 85 °C)	Relative humidity More than 54 % up to 98 %	Relative humidity 2.8 %	
		Frost point from	1-30 °C up to -10 °C	0.30 °C	-
condu hyg Hu		Dew point from	n -10 °C up to 50 °C	0.30 °C	
	Thermal conductivity type hygrometers		m 2.4 g/m³ up to 82.8 g/m³ from -10 °C up to 50 °C)	Absolute humidity 2.2 g/m <sup>3</sup>	-
	Humidity	Frost point from	-30 °C up to -10 °C	0.17 °C	0.20 °C
	generators	Dew Point from	1 -10 °C up to 50 °C	0.10 °C	0.20 °C
		Temperature Point From 5 °C up to 60 °C	Relative humidity from 5 % up to 95 %	Relative humidity 0.4 %	Relative humidity 1.2 %
		(Dew point is from -10 °C up to 50 °C)	Relative humidity more than 95 % up to 98 %	Relative humidity 0.4 %	Relative humidity 1.4 %

<sup>#</sup>All Calibration Procedures are in-house procedures developed by this laboratory.